

Search for the Higgs Boson Decay $H \rightarrow Z\gamma$ with the CMS Experiment

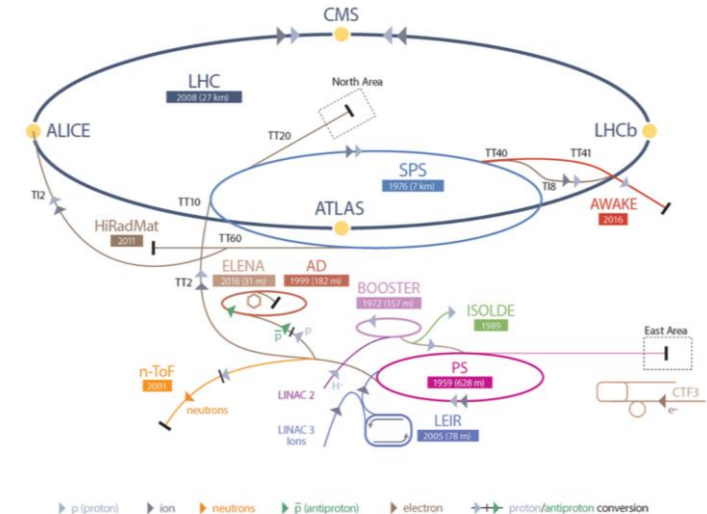
Xingchen Fan on behalf of the CMS
collaboration

PASCOS 2026 Sheffield, UK

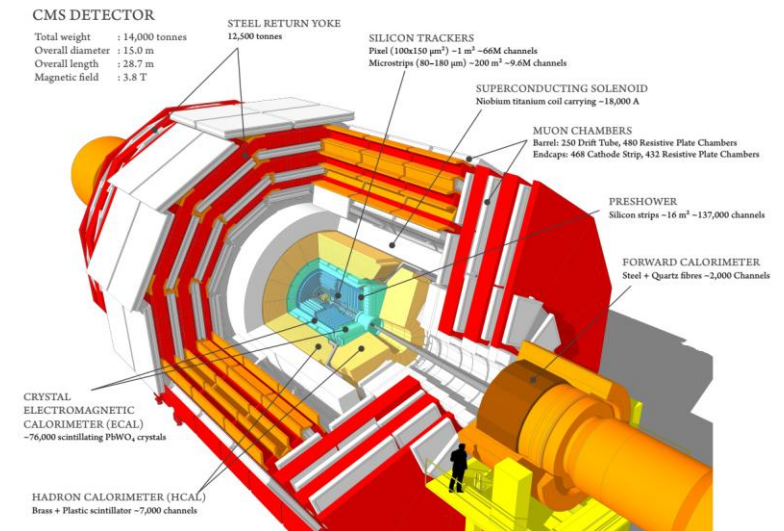


Large Hadron Collider and CMS Experiment

- The Large Hadron Collider (LHC) is the largest circular particle accelerator.
 - Located at CERN, Geneva, Switzerland
 - 27 km circumference, ~100 m underground
 - Colliding protons or heavy ions
- The Compact Muon Solenoid (CMS) is a general-purpose detector at LHC.
 - 14000 tons and 15×29 m
 - Cylindrical design with 4π solid angle coverage
- About 40M collisions recorded per second
 - Trigger system reduces the to ~1kHz
- Data processed by data centers worldwide.
 - ~20PB data annually



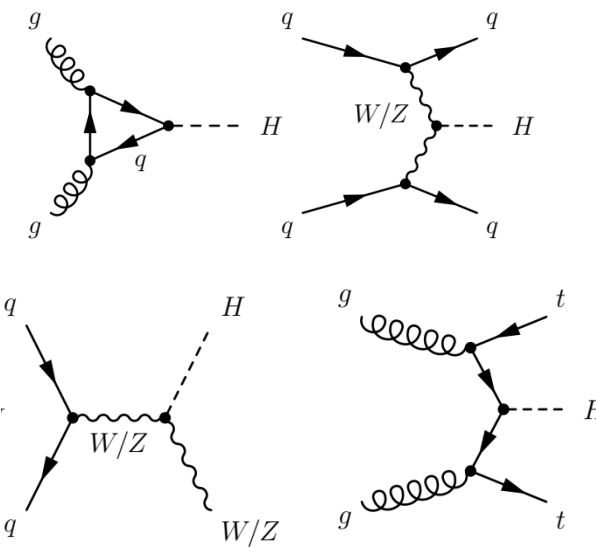
CERN accelerator complex



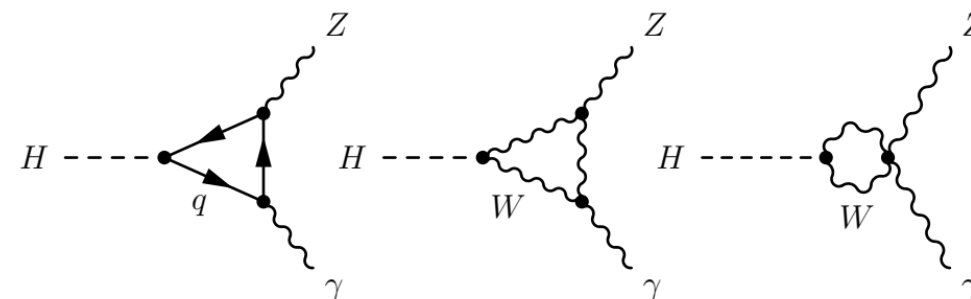
Schematic of CMS detector

H $\rightarrow$ Z γ Process

- H $\rightarrow$ Z γ $\rightarrow$ e⁺e⁻ γ / $\mu^+\mu^-\gamma$ is a rare Higgs decay with SM BR(H $\rightarrow$ Z γ) $\approx 1.54 \times 10^{-3}$
 - All major Higgs production modes are considered
- Any deviation from SM prediction can hint for new physics beyond SM.
 - Higgs imposter, new fields that couple to Higgs, composite Higgs, etc.
- This analysis uses data collected in Run 2 (2016 – 2018) and early Run 3 (2022 and 2023)
 - 10M Higgs bosons produced
 - Expect about 15k events



Higgs boson production modes

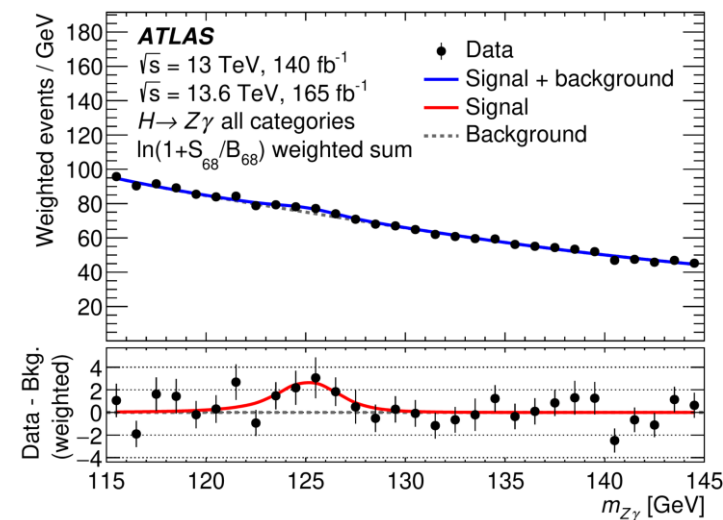
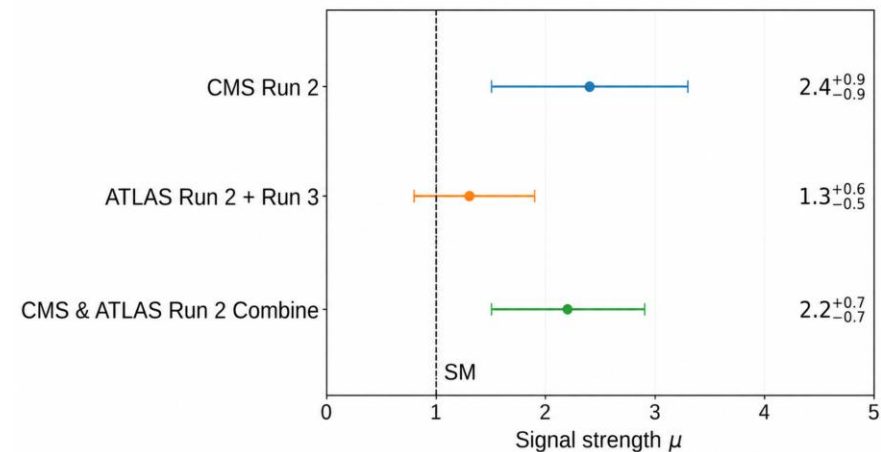


SM H $\rightarrow$ Z γ Feynman diagrams

Results from CMS and ATLAS

- CMS Run 2 [1]: signal strength $\mu = 2.4^{+0.9}_{-0.9}$
- CMS + ATLAS (Run 2) [2]: $\mu = 2.2^{+0.7}_{-0.7}$
 - 1.9 s.d. consistency w/ SM
- ATLAS Run 2 + 2022-2024 [3]: $\mu = 1.3^{+0.6}_{-0.5}$ (305 fb⁻¹)
- Signal strength: observed signal yield/expected signal yield
- Main challenges:
 - Tiny signal
 - Large backgrounds from non-resonant Z with photon
 - Avoid bias in the signal extraction procedure

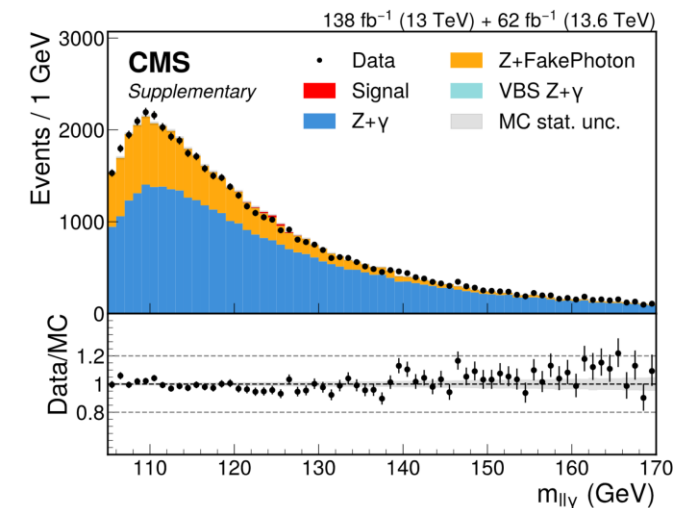
[1] [JHEP 05 \(2023\) 233](#), [2] [Phys.Rev.Lett. 132 \(2024\) 021803, 2024](#).
 [3] [HIGP-2024-19](#)



ATLAS weighted post-fit plot [3]

Analysis Strategy

- Signal extracted from the distributions of the invariant mass of Higgs candidates, $m_{ll\gamma}$
- Data collected using single and dilepton triggers
- MC simulated samples are used to study background and signal
 - Two major non-resonant backgrounds are $Z+\gamma$ and $Z+\text{fake photon}$
- Physics object selection and baseline selection to improve sensitivity
- Events are categorized into various categories based on Higgs production modes
 - Boosted Decision Tree (BDT) and kinematic variable selections
- Parametric models are used to fit the $m_{ll\gamma}$ distributions
- A sequence of tests is developed to ensure the parametric models can describe the shape with minimal bias



Data vs. MC shape comparison
in one of the ggF categories

Event Categorization

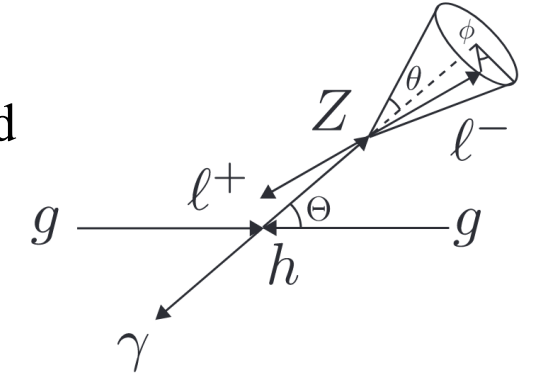
- After baseline selection, events are sorted into inclusive & non-overlapping categories
- Use object multiplicity and other basic event features to target all major Higgs production modes

Category name	Lepton, jet, and p_T^{miss} requirements				Optimization selections		
	N_ℓ	N_{jet}	$N_{\text{b,med.}}$	p_T^{miss} [GeV]	$m_{\ell\ell}$ [GeV]	$p_T(\ell\ell\gamma)/m_{\ell\ell\gamma}$	I_{mini}
ggF	$= 2$	≤ 1		< 90	Further binned by BDT		
VBF	$= 2$	≥ 2	$= 0$		Further binned by BDT		
$t\bar{t}H$ leptonic	$= 3$ ≥ 4	≥ 3 ≥ 1	≥ 1 ≥ 1				< 0.1
VH $N_\ell \geq 3$	≥ 3		$= 0$	> 30		> 0.3	< 0.15
$t\bar{t}H$ hadronic	$= 2$	≥ 5	≥ 1		[85,95]		
VH p_T^{miss}	$= 2$	≤ 1		> 90		> 0.4	
Untagged	Events passing baseline selection not in another category						

([HIG-25-010](#))

ggF and VBF BDT

- Kinematic variables selection optimized by signal and background separation and no correlation with $m_{ll\gamma}$
 - Higgs variables and jet variables
 - Used as BDT input variables
- Good data vs MC agreement

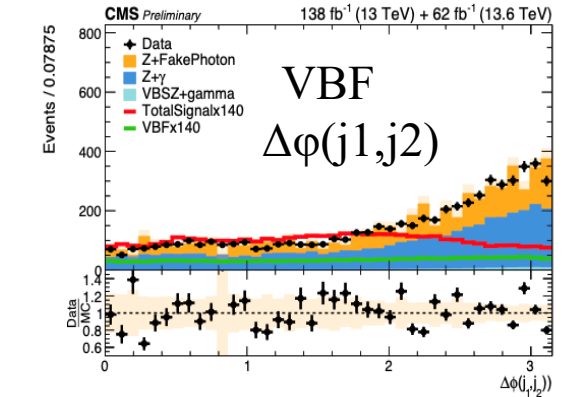
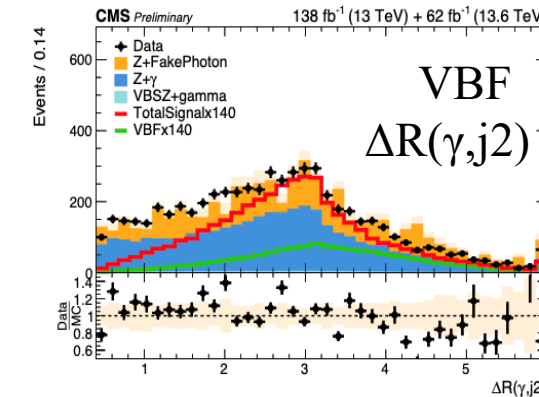
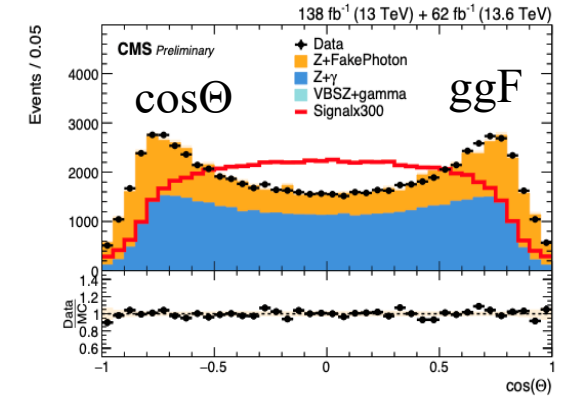
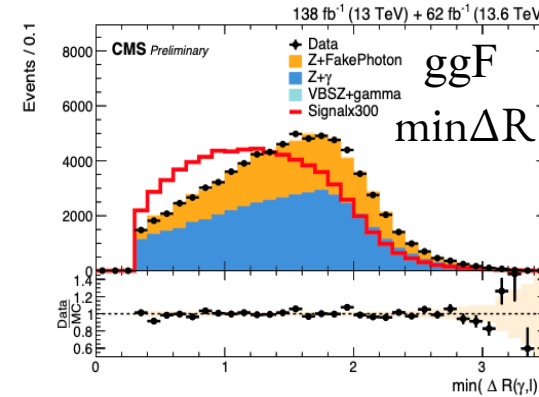


ggF BDT inputs:

Type	Variables
Boosted Higgs	$pT_{ll\gamma}/m_{ll\gamma}$
Photon Quality	photon ID MVA $\sigma_{\gamma}/E_{\gamma}$
Angles Between Final State Particles	$\min \Delta R(l, \gamma)$
	$\max \Delta R(l, \gamma)$
	$\cos \Theta$
	$\cos \theta$
	ϕ
Angles Of Final State Particles	$ \eta_{\gamma} - \eta_{ll} $
	$\Delta R(j_1, \gamma)$
	$\eta(l_1)$
	$\eta(l_2)$
Jet Kinematics	$\eta(\gamma)$
	$\eta(j_1)$
	$j_1 p_T$
	N_{jets}
System Balance	system p_T balance
	$\Delta \phi(H^{miss}, \gamma)$
	$\Delta \phi(ll\gamma, j_1)$

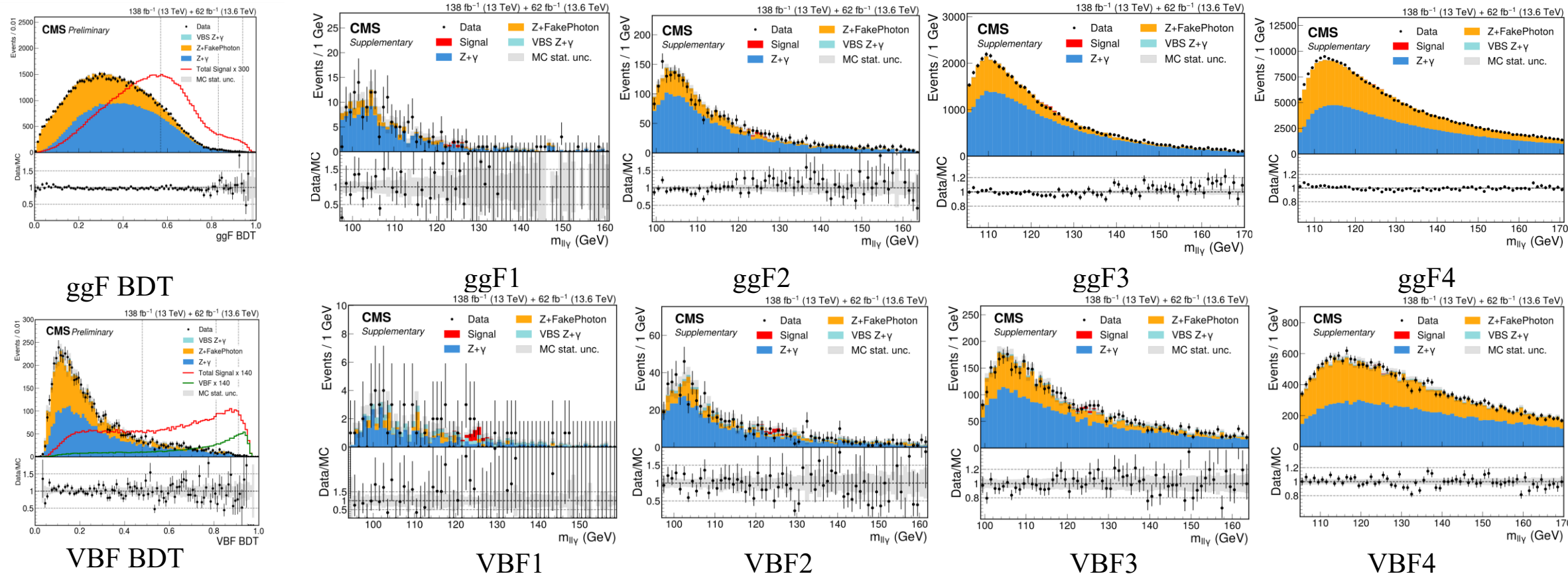
VBF BDT inputs:

Type	Variables
Boosted Higgs	$pT_{ll\gamma}/m_{ll\gamma}$
Photon Quality	photon ID MVA $\sigma_{\gamma}/E_{\gamma}$
Angles Between Final State Particles	$\min \Delta R(l, \gamma)$
	$\max \Delta R(l, \gamma)$
	$\cos \Theta$
	$\cos \theta$
	ϕ
Angles Of Final State Particles	photon zeppenfeld
	$\Delta R(j_1, \gamma)$
	$\Delta R(j_2, \gamma)$
	$\eta(l_1)$
Jet Kinematics	$\eta(l_2)$
	$\eta(\gamma)$
	$m(j_1, j_2)$
	$\Delta \eta(j_1, j_2)$
System Balance	$\Delta \phi(j_1, j_2)$
	$j_1 p_T$
	$j_2 p_T$
	N_{jets}
System Balance	system p_T balance
	$\Delta \phi(H^{miss}, \gamma)$
	$\Delta \phi(ll\gamma, j_1)$



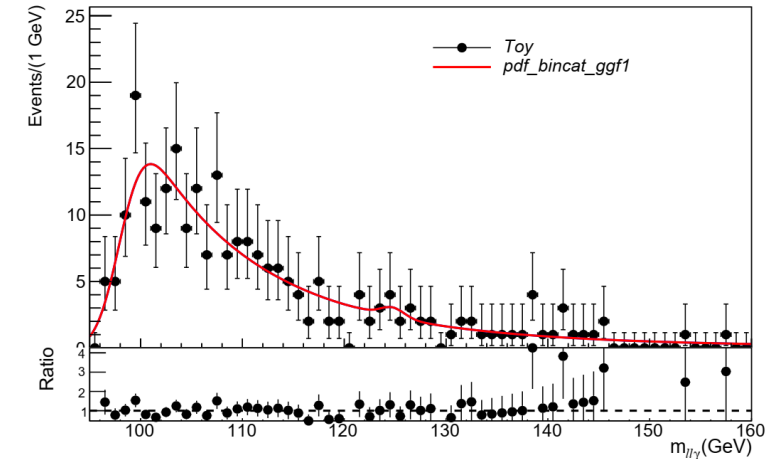
ggF and VBF Categories

- Divide selected events into 4 categories based on their BDT scores.
 - Maximize cut-and-count significance in 120-130 GeV window: $Z_{cc} = \sqrt{2[(N_S + N_B) \cdot \ln(1 + N_S/N_B) - N_S]}$
- Two major backgrounds: $Z+\gamma$, $Z + \text{fake photon}$

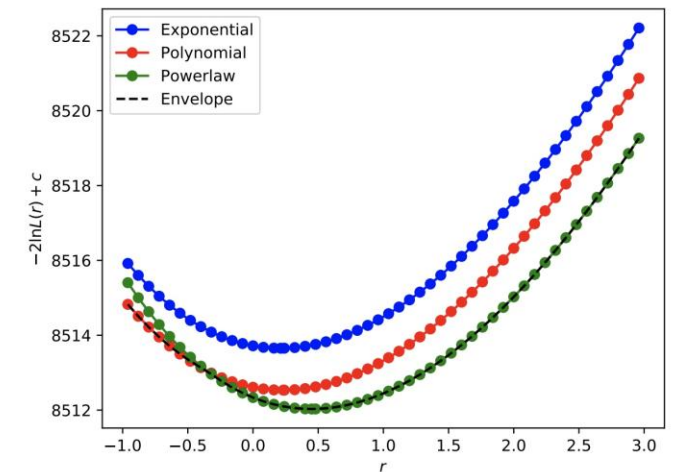


Fit Strategy

- Parametric binned maximum likelihood fit to $m_{ll\gamma}$ distribution in data (ROOT/RooFit)
- For each category, fit over one $m_{ll\gamma}$ distribution summing Run 2+Run 3 and lepton flavors
 - Thirteen category simultaneous fit
- Background model using discrete profiling method where the fit can pick a model from a validated envelope
 - [Discrete profiling method](#): The best-fit model is selected from a group of functional models, referred to as **envelope**. A discrete parameter, index, is floating for the choice of models.



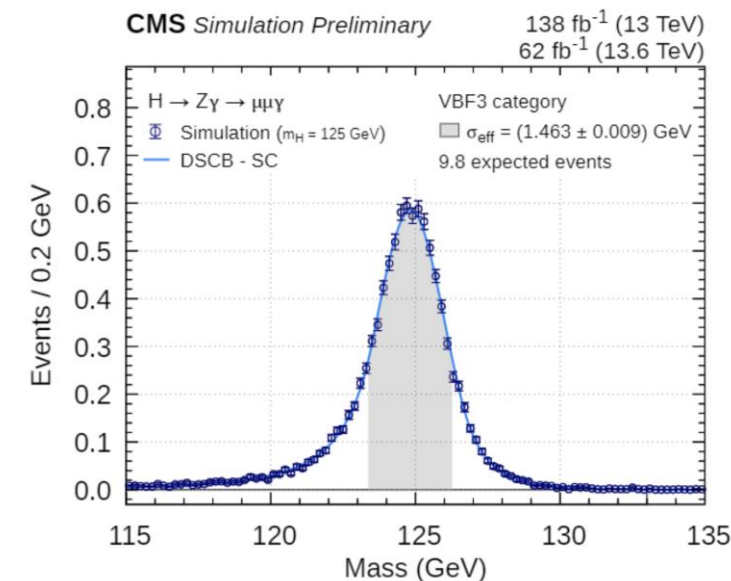
Toy data from one category showing what S+B fit looks like



Discrete profiling ([CMS Combine](#))

Signal Model

- Double-Sided Crystal Ball (DSCB) with symmetric core as the signal model.
- Model parameters are determined by fits to signal MC samples
 - MC samples available at $m_H = 120, 125$, and 130 GeV.
 - Model mean and sigma values at $m_H = 125.38$ GeV are extrapolated from linear fit to results at three mass points.
- Model parameters are fixed for final fit, but nuisance parameters are floating to account for scale/resolution uncertainties.
- In each category, the signal model is an addition of two DSCB, one for each lepton flavor.
 - Years and production modes are not separated.
- Same model from the 125 GeV simulation for the small resonant background from $H \rightarrow \mu\mu + \gamma_{\text{FSR}}$



Signal model fit to VBF3 MC
muon channel at $m_H = 125$ GeV

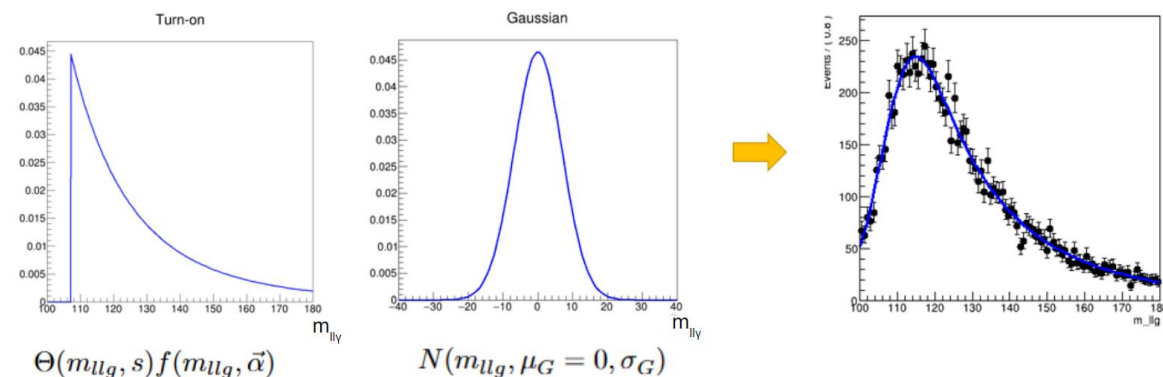
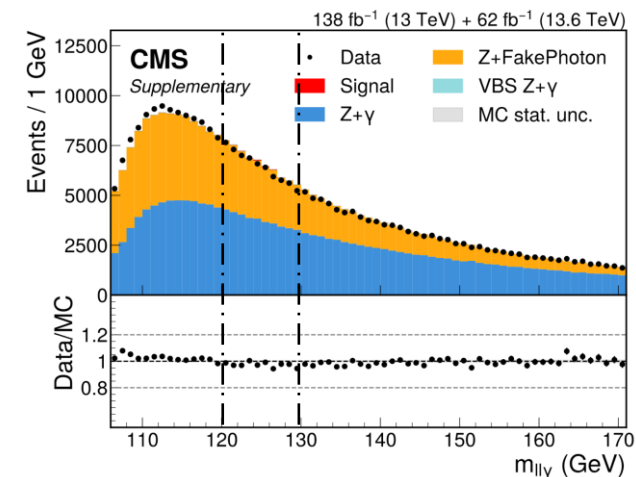
Background Model

- With the selection, the background in general has a peak below the signal window and a falling region over the signal window.
 - Signal window: 120 – 130 GeV
- The convolution model is defined as

$$\mathcal{F}(m_{\ell\ell\gamma}; \mu_G, \sigma_G, s, \vec{\alpha}) \equiv \int_{-\infty}^{\infty} \mathcal{N}(m_{\ell\ell\gamma} - t; \mu_G, \sigma_G) \Theta(t; s) f(t; \vec{\alpha}) dt$$

where N is the Gaussian with $\mu_G = 0$, Θ is the step function at s and f is an empirical function.

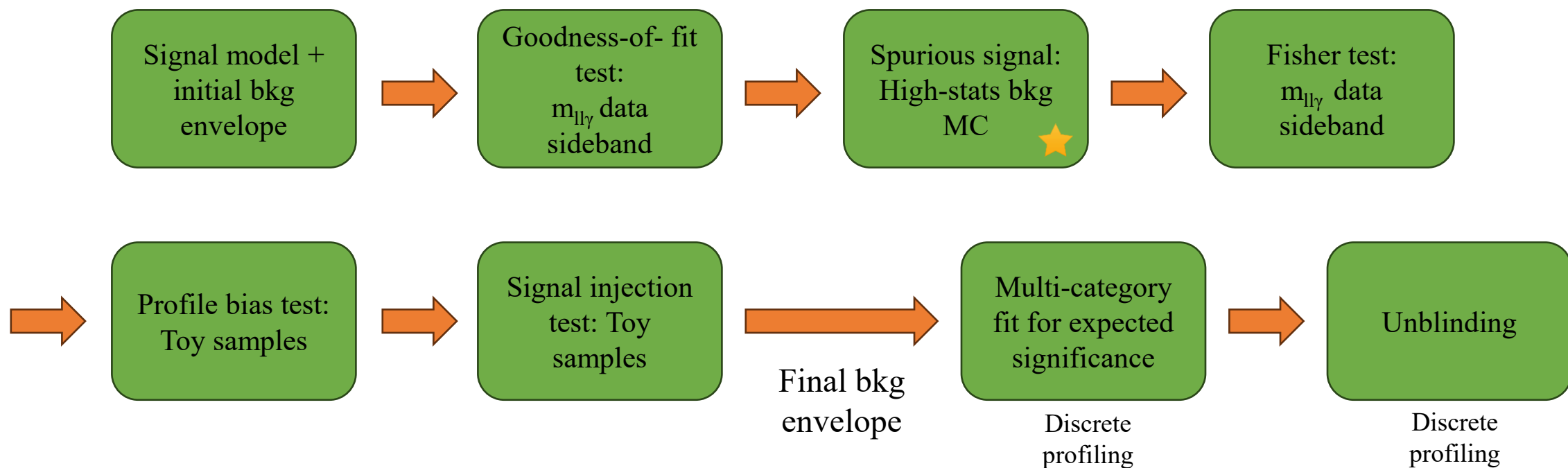
- Different families of functions are used
- Asymmetric Gaussian variants
 - Modify the mean and sigma so that they are $m_{\ell\ell\gamma}$ dependent



Convolution of an empirical function with a Gaussian

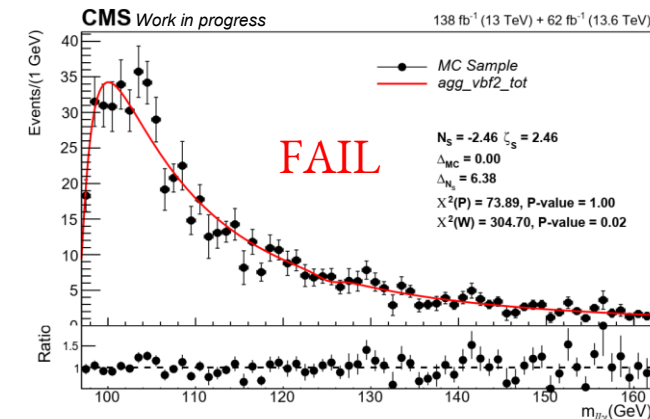
Fit Test Sequence

- To ensure the robustness and reliability of the final fit, background models must go through a sequence of tests
 - Good flexibility and with small fit bias
- A validated final background envelope is created for discrete profiling at the end of the sequence.

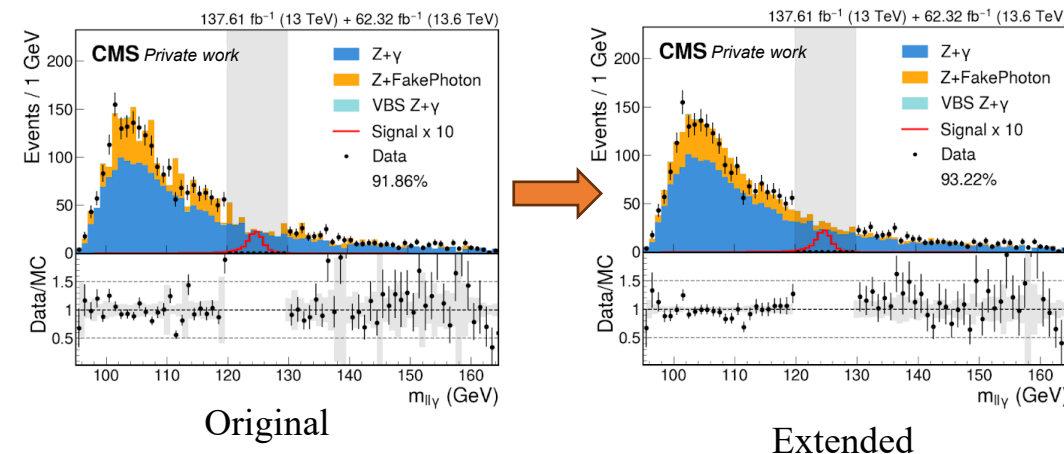


Spurious Signal Test and Low MC Statistics Challenge ★

- Use the **background-only high statistics simulation** to test whether the S+B fit with a given background model would bias the signal measurement, giving “spurious signal”
- Central produced Drell-Yan MC sample has too low statistics.
 - Large fluctuation in **Z + fake photon**
- We study the physics of Drell-Yan process and generate more events with different methods, depending on the sources.
 - Events whose photon from pile-up: event mixing method
 - Events whose photon from jets: private MC with gen-level filter
- The high-stat **Z + fake photon** sample is used only in the BDT training and spurious signal test.

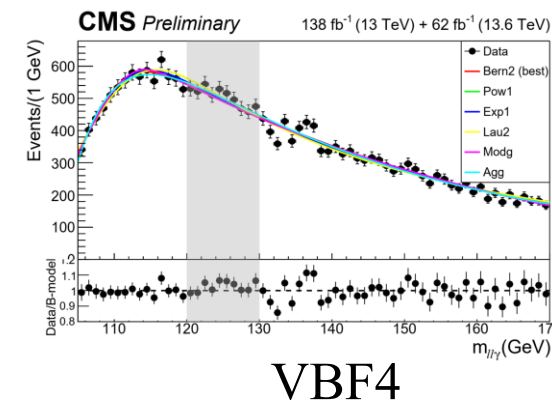
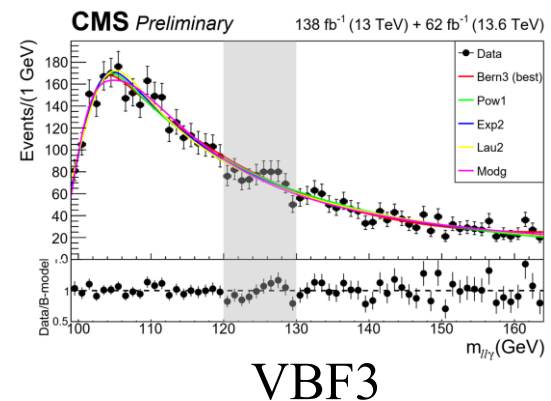
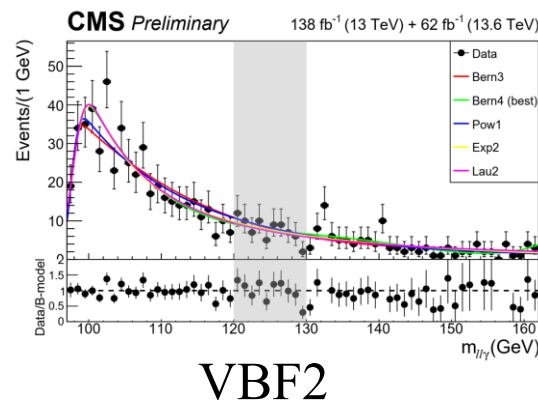
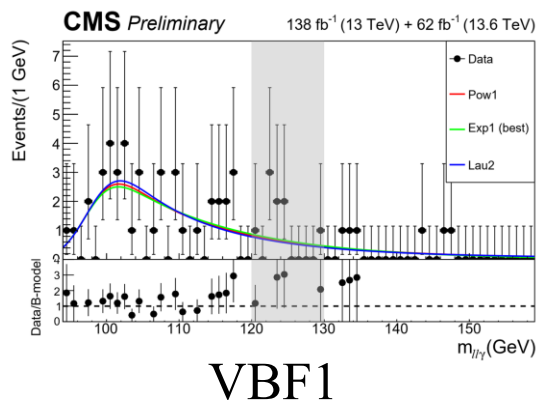
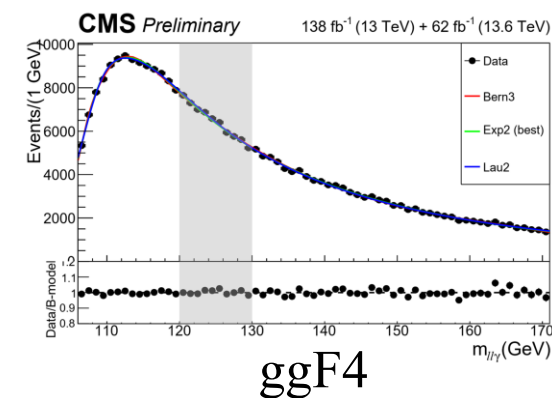
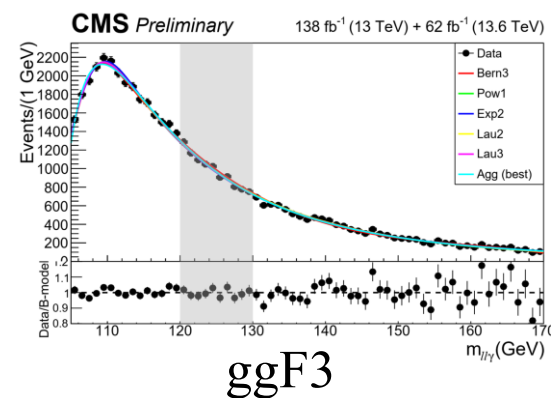
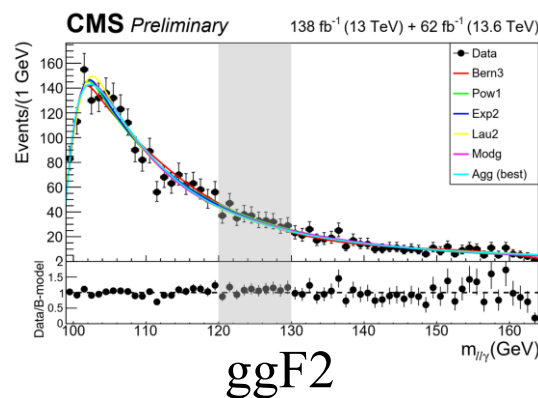
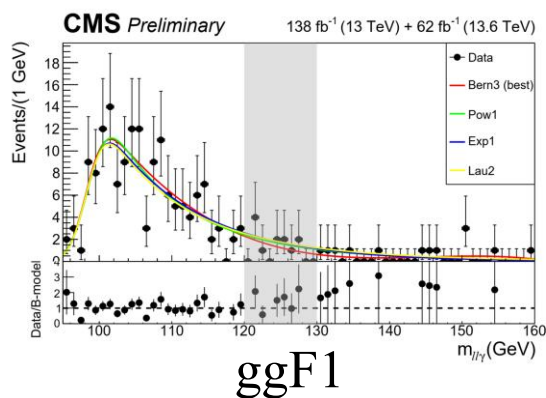


S+B fit of Exp1 bkg model over the high-stat MC of VBF2. This model fails the test with high spurious signal.



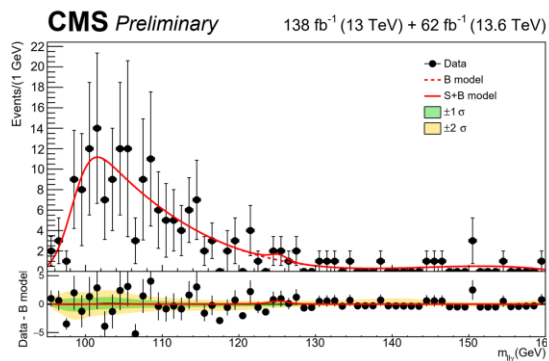
Final Background Envelopes

- Envelope functions are from data sideband fits.
- Scope of background functions restricted by the test sequence.

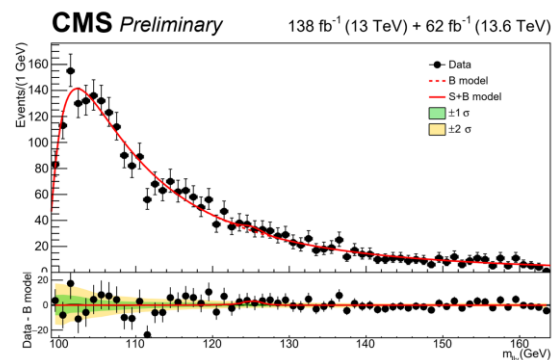


Analysis Results - ggF and VBF Categories

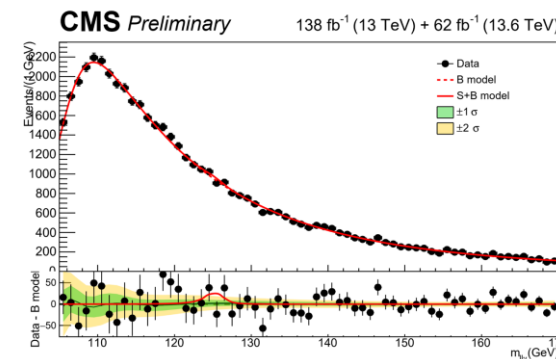
- S+B from simultaneous fit
- Fit provides good description of the data



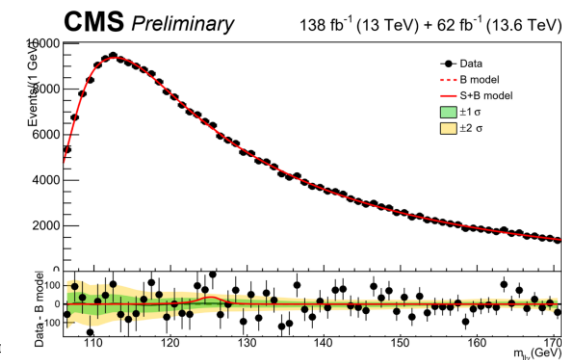
ggF1



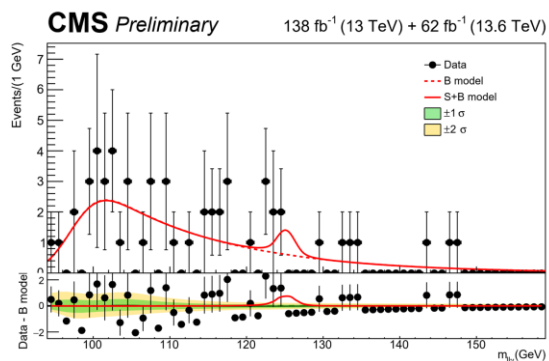
ggF2



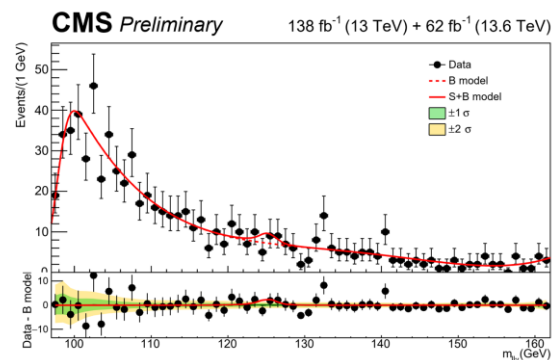
ggF3



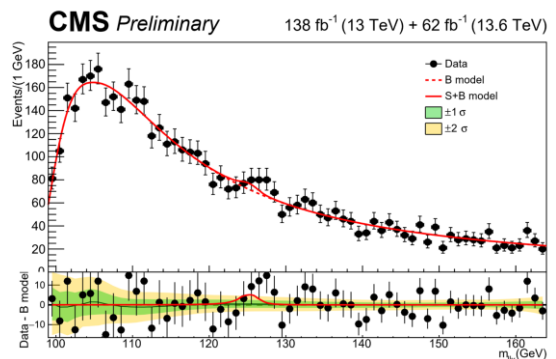
ggF4



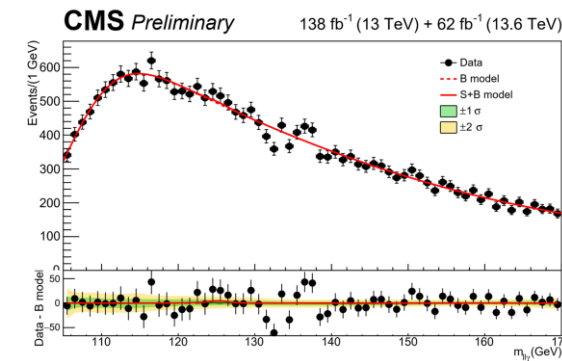
VBF1



VBF2



VBF3



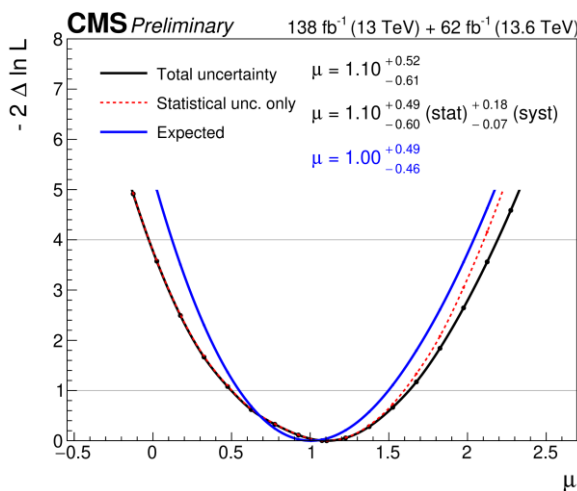
VBF4

(HIG-25-010)

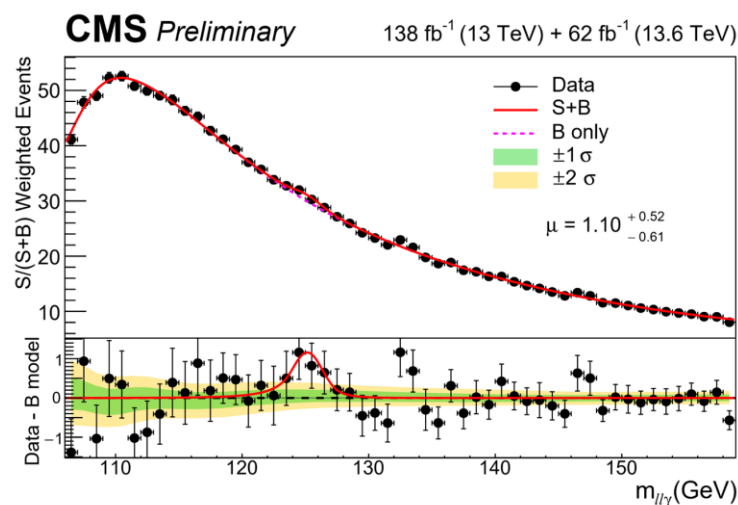
Analysis Results – Signal Strength and Significance

([HIG-25-010](#))

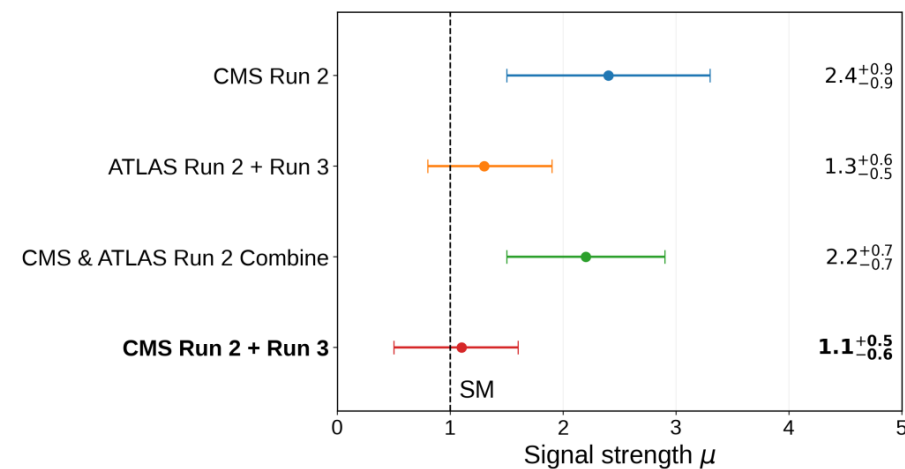
- Observed signal strength: $\mu = 1.10^{+0.52}_{-0.61}$
- Observed (expected) significance: **1.9 σ (2.3 σ)**
- Weighted final fit plot over the common range of 13 categories
 - Categories weighted by expected $S/(S+B)$ in 120 – 130 GeV window and combined
- Channel Compatibility: p-value = 0.75



NLL scan



Weighted final fit plot



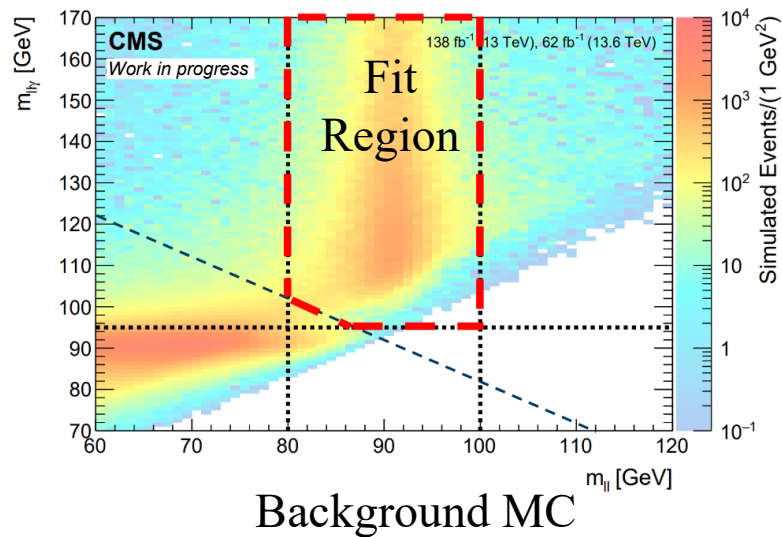
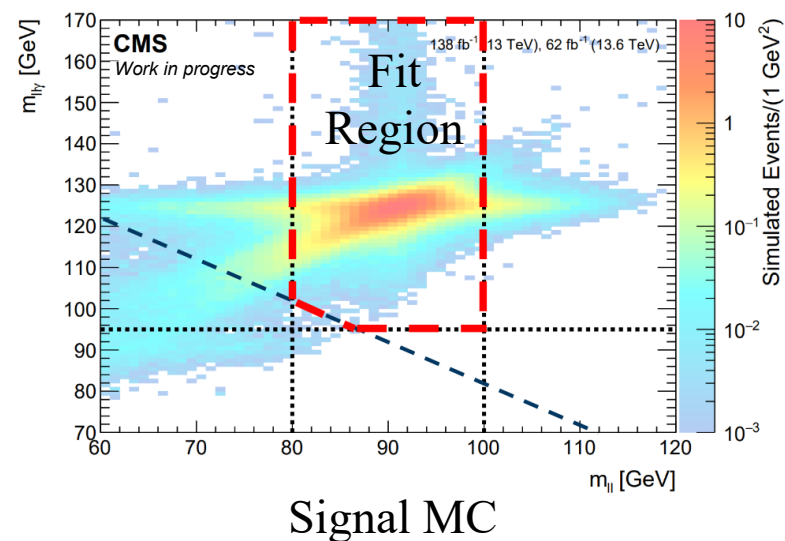
Summary

- I present the search for $H \rightarrow Z\gamma$ with Run 2 and 2022 + 2023 data at the CMS experiment.
- Highlights of the analysis:
 - Thorough trigger study and refined event selection
 - Robust BDT performance and categorization
 - A sequence of fit tests with extra care of bias
 - New method to extend MC statistics of Drell-Yan process
- With the observed signal strength $\mu = 1.10^{+0.52}_{-0.61}$, the result is consistent with the SM within 0.2σ .
- Thank you for your attention!

BACKUP

Event Selection

- Object selections
 - Photons: $p_T > 15$ GeV, $|\eta| < 2.5$, $\Delta R_{\min}(l, \gamma) > 0.3$, etc.
 - Electrons: $p_T > 7$ GeV, $|\eta| < 2.5$, di-electron or single-electron trigger, etc.
 - Muons: $p_T > 5$ GeV, $|\eta| < 2.4$, di-muon or single-muon trigger, etc.
 - Jets: $p_T > 30$ GeV, $|\eta| < 4.7$, tight jet ID, etc.
- Baseline selection
 - $N_\gamma \geq 1$, $N_e \geq 2$ or $N_\mu \geq 2$
 - $80 \text{ GeV} < m_{ll} < 100 \text{ GeV}$, $p_T(\gamma)/m_{ll\gamma} > 15/110$, $m_{ll} + m_{ll\gamma} > 185 \text{ GeV}$



- Event selection mainly rejects Z + FSR γ and soft γ background
- Optimized for max background rejection while maintaining background shape and signal efficiency

ggF and VBF Categorization Strategy

- ggF: 90% of signal events are in this category.
- VBF: category with highest significance
- Extensive studies gone into studying the separation of these two categories
 - Optimized for highest overall sensitivity and simplicity
 - BDTs are used to further divide them into sub-categories
- BDT training strategy:
 - Use MC samples ($120 < m_{ll\gamma} < 130$ GeV) in training:
 - Background: $Z+\gamma$, high statistics $Z+\text{fake } \gamma$ samples, VBS $Z+\gamma$
 - Signal: ggF, VBF
 - Train Run 2 + early Run 3 (2022+2023) combined
 - Four-fold training & validation method
 - Divide MC samples into 3 parts (50% training, 25% validation, 25% testing)
 - More stable BDT performance and better usage of simulated samples

	25%	25%	25%	25%
1 st fold	Training set		Validation set	Test set
2 nd fold	Test set	Training set		Validation set
3 rd fold	Validation set	Test set	Training set	
4 th fold	Training set	Validation set	Test set	Training set

Systematics

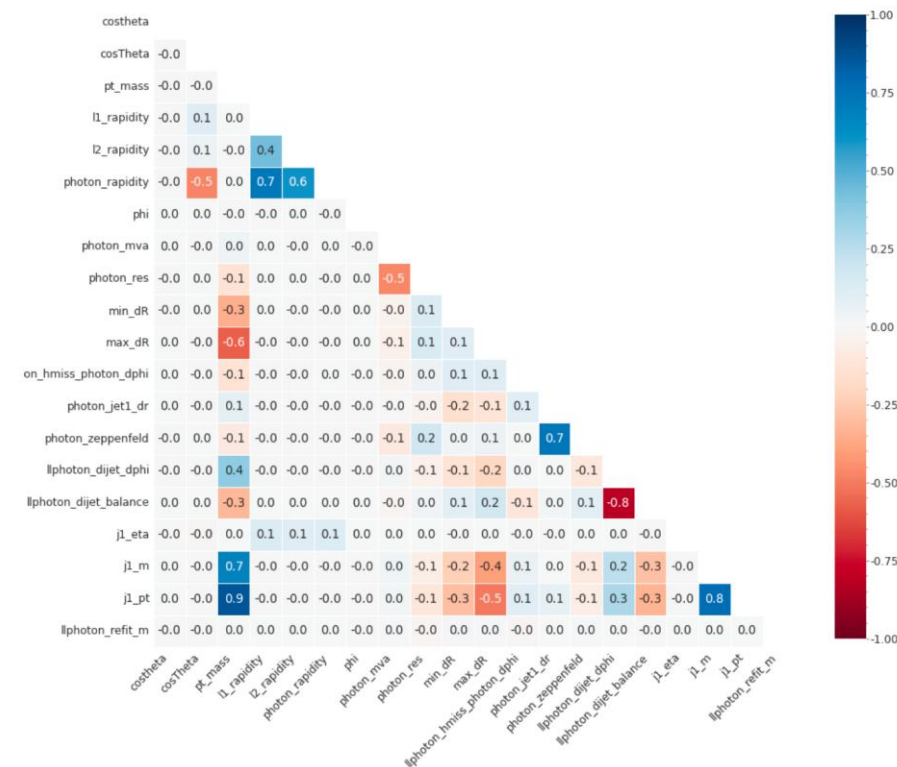
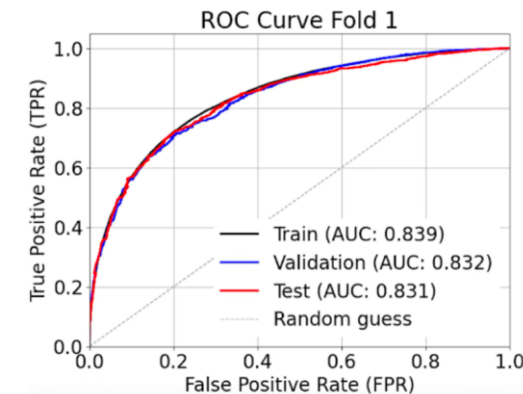
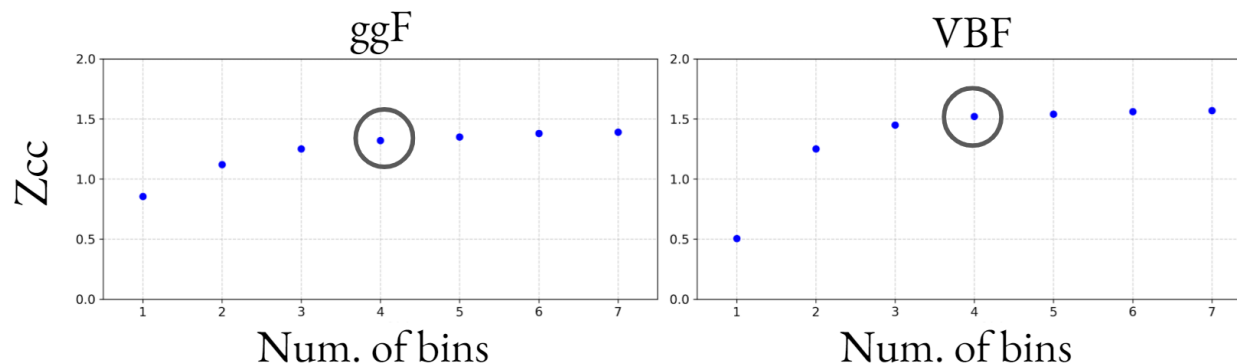
- Incorporated by allowing signal model to vary in shape and normalization
- Analysis statistically limited
 - Statistical uncertainty $+0.49/-0.60$
 - Overall systematic uncertainty $+0.18/-0.07$
- Summary of the uncertainty sources:

Uncertainty source	Impact on μ
Statistical uncertainty	$+0.50, -0.60$
Background shape	$+0.08, -0.36$
Signal systematic uncertainty	0.11
Fixed-order calculations	0.09
Lepton and photon energy scale and resolution	0.04
Photon quality	0.04
PDFs, α_S , and m_q	0.03
Lepton and photon reconstruction, identification, and trigger efficiency	0.02
Luminosity and pileup	0.01
Underlying event and parton shower	0.01
Jet and p_T^{miss} energy, b tagging, simulation statistics	< 0.01

ggF & VBF BDT Optimization

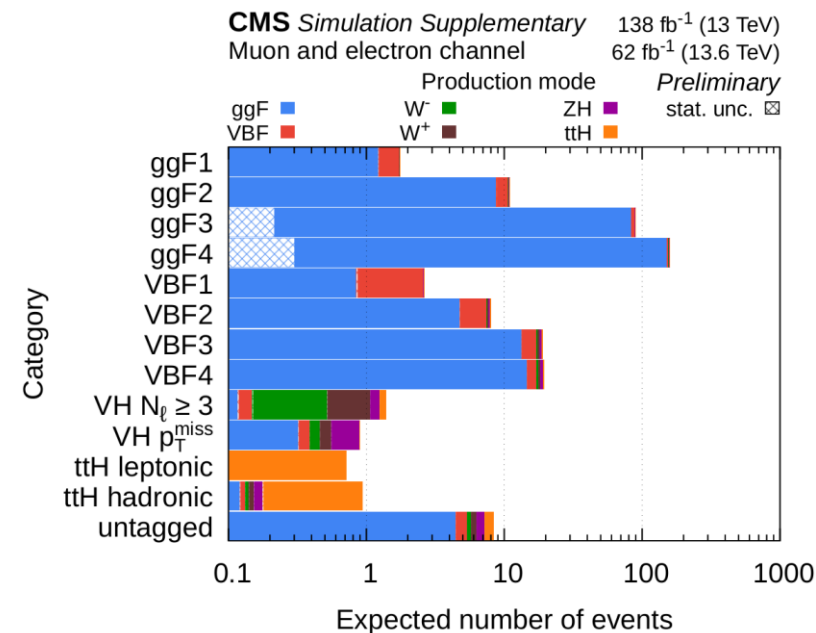
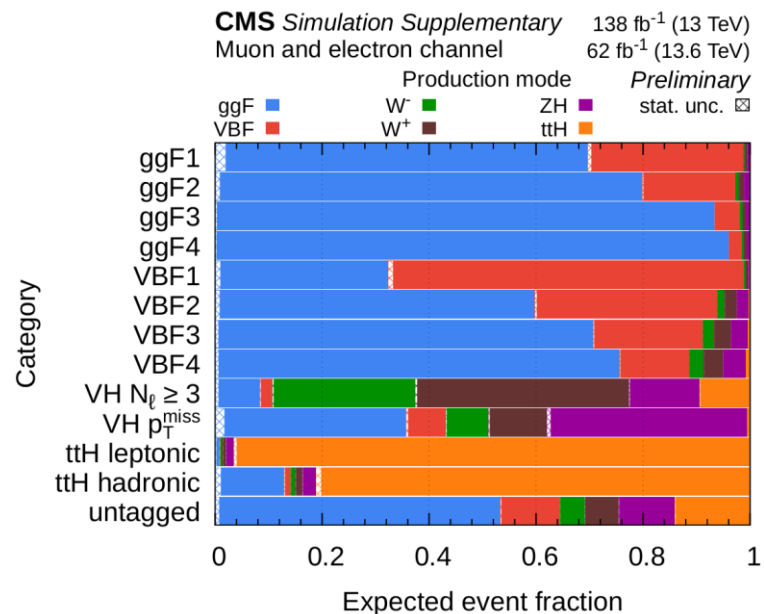
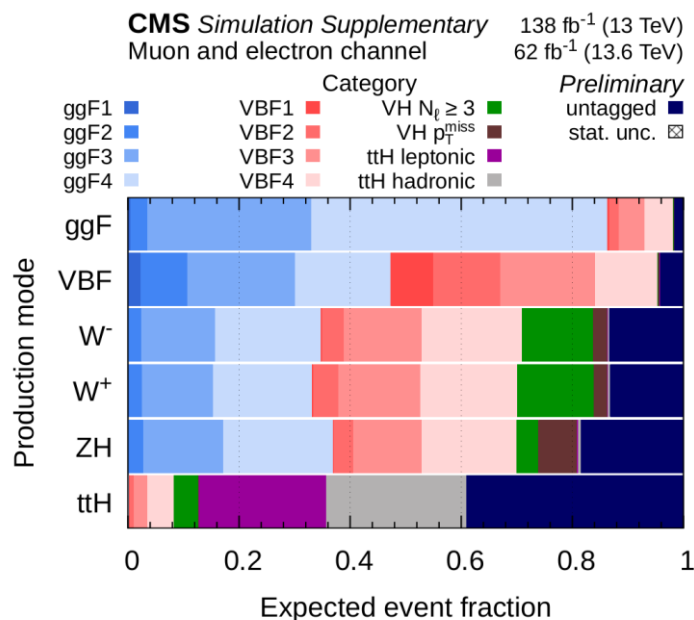
- Input variables selection optimized by S vs B separation power & correlation with $m_{ll\gamma}$
- Hyperparameters optimized to minimize overtraining (validation vs training) and to ensure consistent behavior among folds
- Number of bins optimized by

$$Z_{cc} = \sqrt{2[(N_S + N_B) \cdot \ln(1 + N_S/N_B) - N_S]}$$



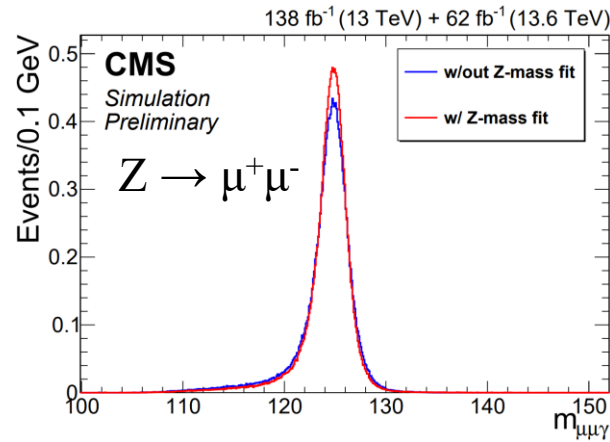
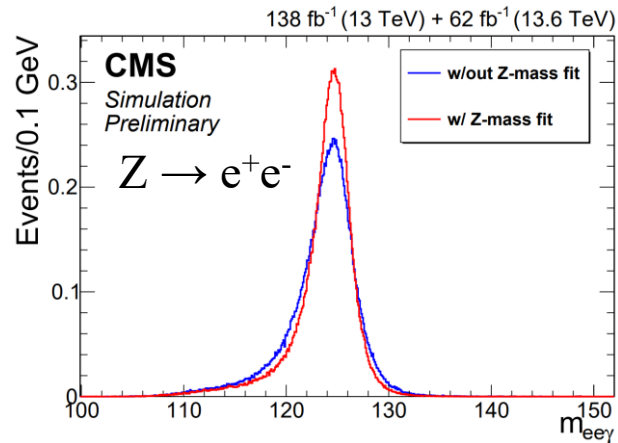
Categorization Output

- ggF & VBF categories have comparable cut and count significance (Z_{cc})
- VBF highest bin: 70% VBF production
- Associated production enriched in corresponding categories



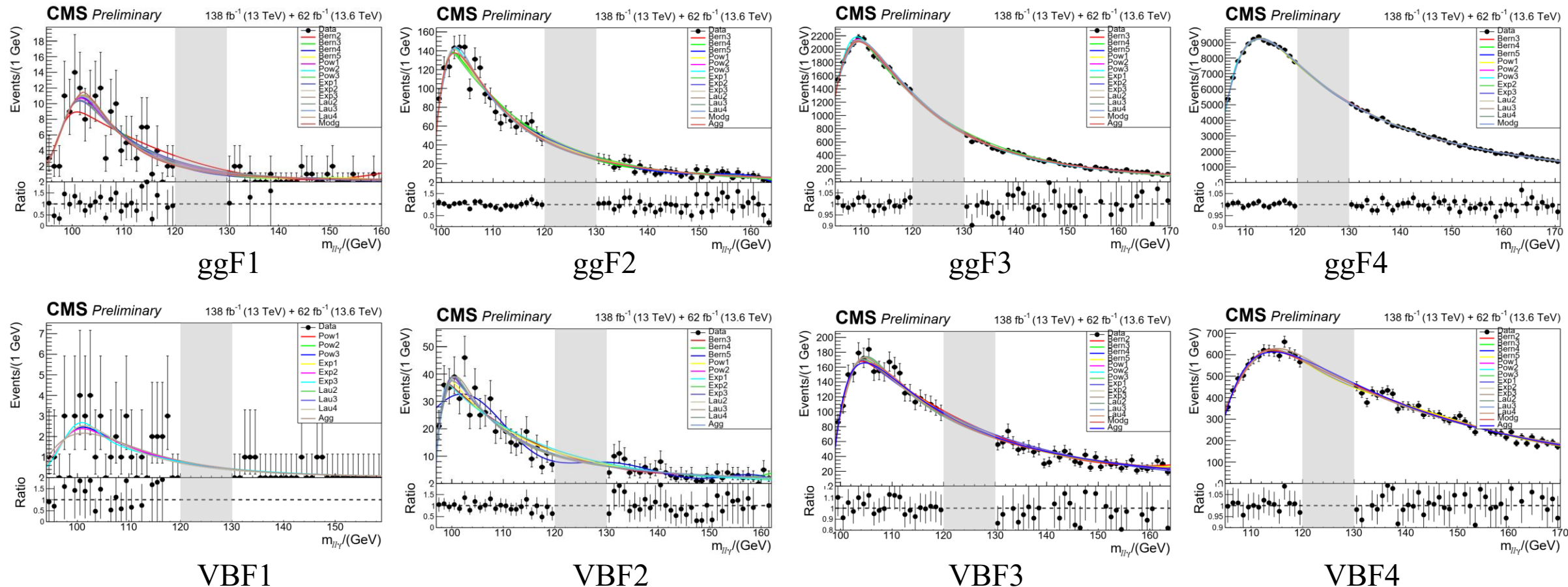
Z-Line Shape Constraint Fit

- Use maximum likelihood estimation with fit of MC truth m_Z line shape
 - Incorporate FSR photon recovery for muons



- Improve $m_{ee\gamma}$ resolution $\sim 20\%$ and $m_{\mu\mu\gamma}$ resolution $\sim 10\%$
 - Signal resolution: e: 1.4-1.8 GeV μ : 1.2-1.5 GeV
- No shift in background $m_{ll\gamma}$ shape

Data Sideband Goodness-of-fit Test

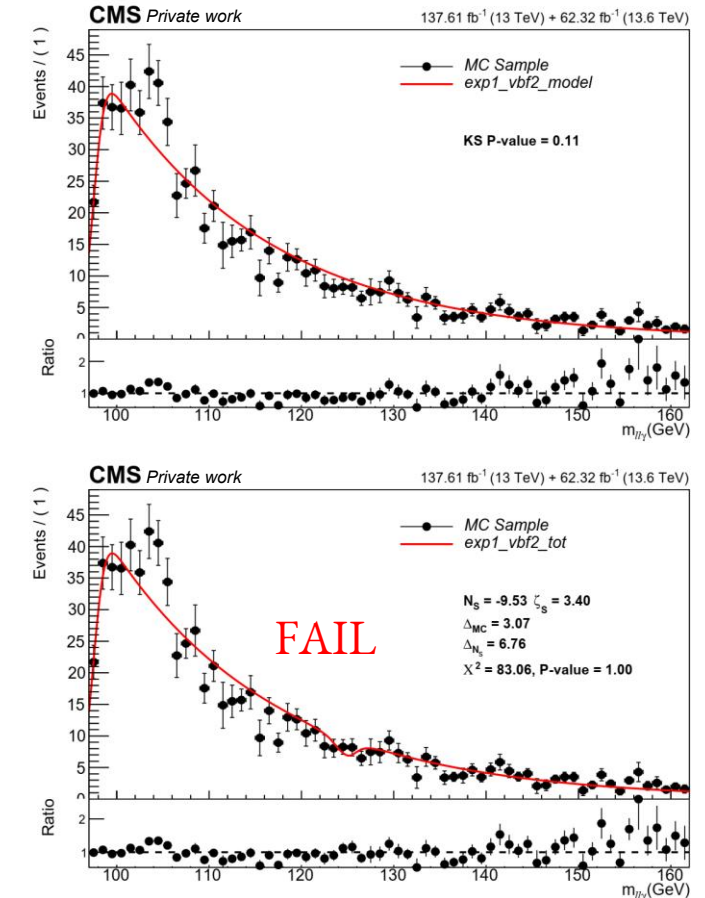


- Basic test to ensure the selected background models can fit the data sideband.
- χ^2 binned fit and Kolmogorov–Smirnov (KS) test as criteria.
- Models passing this initial test form an initial envelope to be optimized in the following tests.

Spurious Signal Test

- Use the **background-only high statistics simulation** to test whether the S+B fit with a given background model would bias the signal measurement, giving “spurious signal”
 - Use the **extended DY** introduced before.
- The spurious signal is defined as $|\zeta_s| = \max(0, |N_s| - 2\Delta_{MC})$
 - N_s is the signal yield from the fit
 - Δ_{MC} is the error of the signal yield representing the statistical uncertainty of the MC sample
 - ΔN_s is also the error of the signal yield but representing the expected uncertainty of the data
- To pass the test, on top of a good fit (χ^2 p-value > 0.05),

$$|\zeta_s| < 20\% \times \Delta N_s \quad \text{or} \quad |\zeta_s| < 10\% \times N_{\text{exp signal}}$$



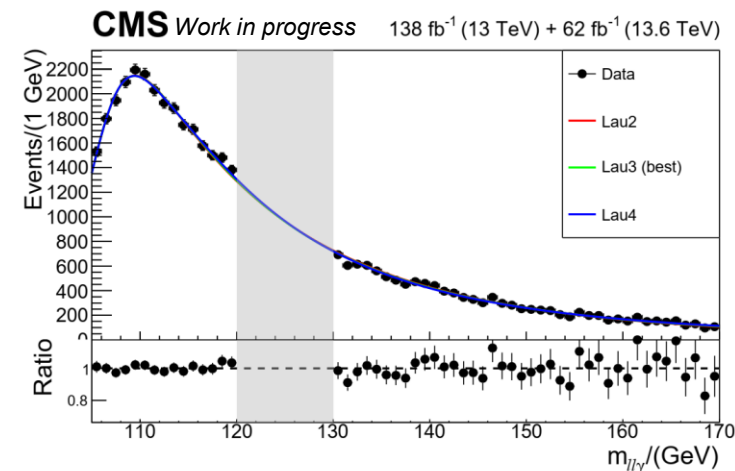
B-only fit and S+B fit of Exp1 bkg model over the high-stat MC of VBF2.
Exp1 fails the test with $\zeta = 3.40$

Fisher Test

- To decide # degrees of freedom (DoF) to use: Fisher test probes marginal improvement that extra DoFs can bring to the background function.
- Data sideband negative log-likelihood (NLL) fit of the background functions from the same family, use the difference between NLL to select functions
- Quantity F follows the χ^2 ($k = \Delta n$) distribution where Δn is the difference of DoF of two models in the same family. P-value of the test is:

$$p = P(F > 2(NLL(n) - NLL(n + \Delta n)) | \chi^2(\Delta n))$$

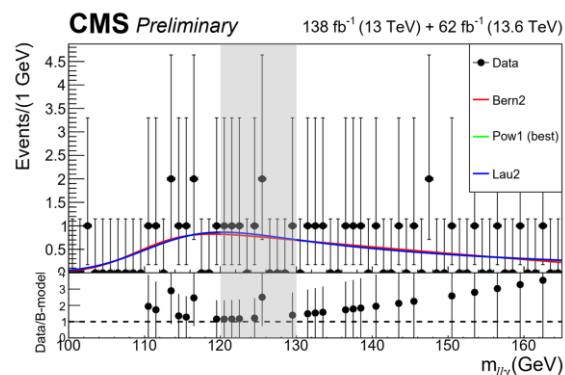
- If p-value < 0.05 , the model with the higher DoF is preferred, otherwise only the lower DoF model is kept in the envelope.



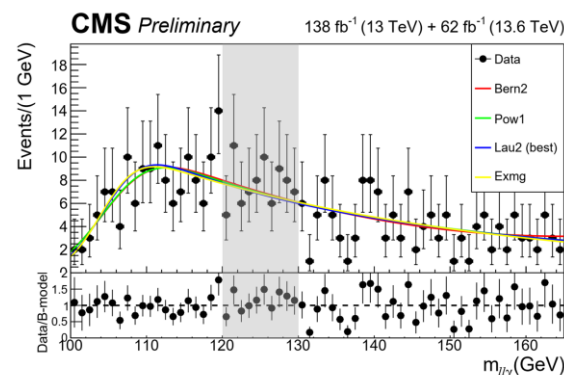
F test in the Laurent series family in ggF3 category. Lau4 has no noticeable improvement over Lau3, thus being removed.

Final Background Envelopes

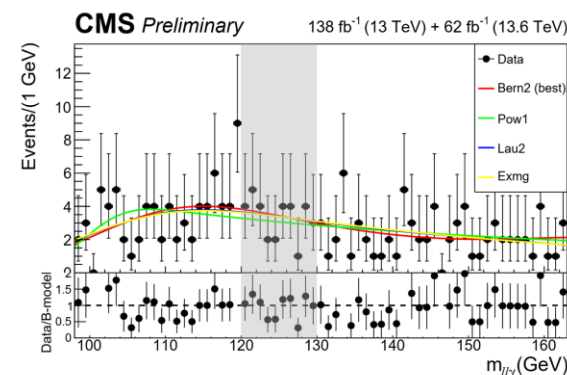
- Envelope functions are from data sideband fits.
- No spurious signal test for these categories due to lack of statistics.



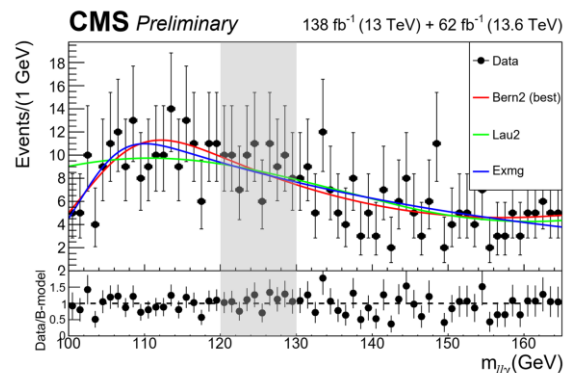
ttH leptonic



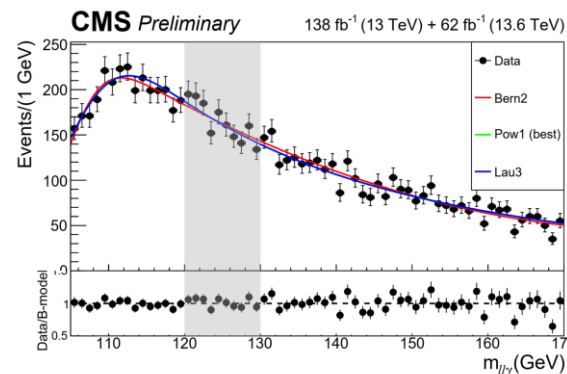
VH $N_{\text{lep}} \geq 3$



ttH hadronic



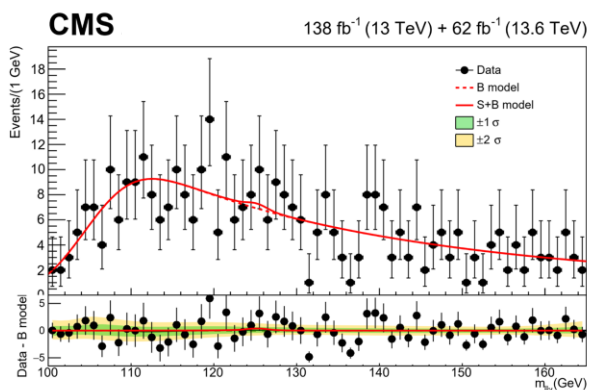
VH p_T^{miss}



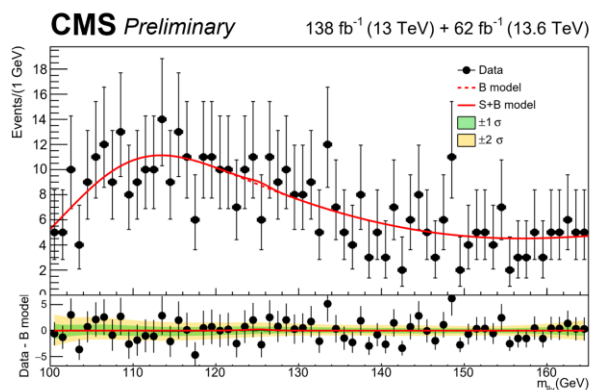
Untagged

Analysis Results - VH and ttH Categories

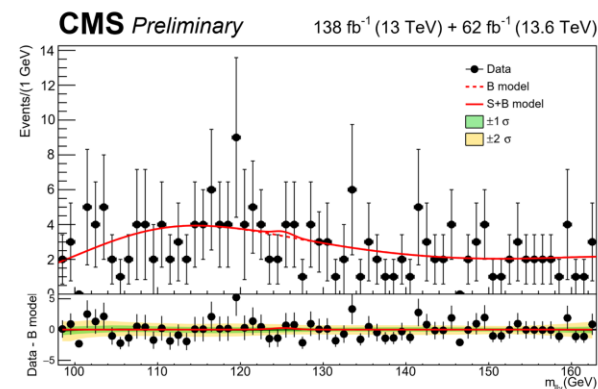
- S+B from simultaneous fit
- Fit provides good description of the data



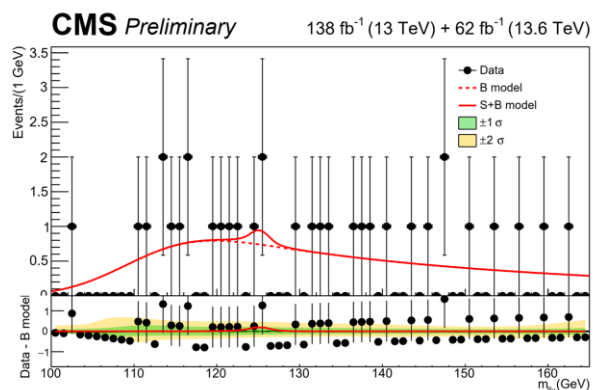
VH $N_1 \geq 3$



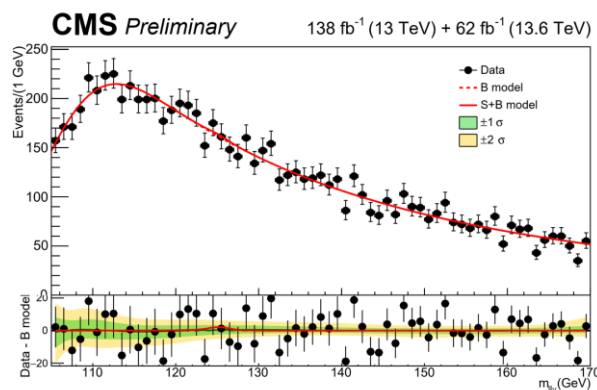
VH p_T^{miss}



ttH hadronic



ttH leptonic

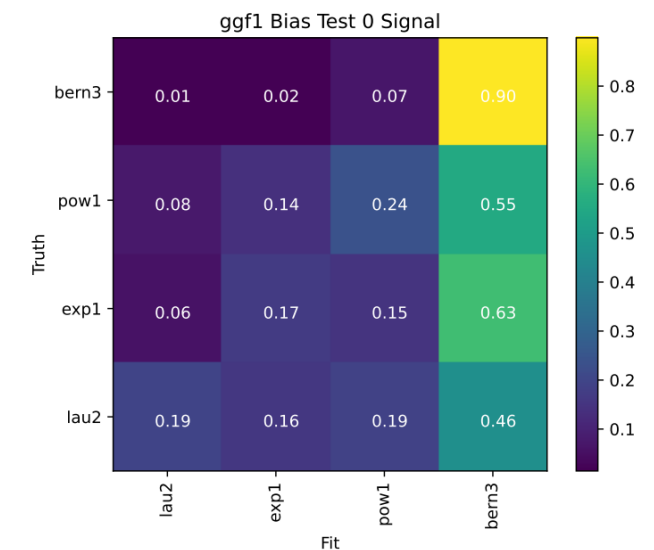
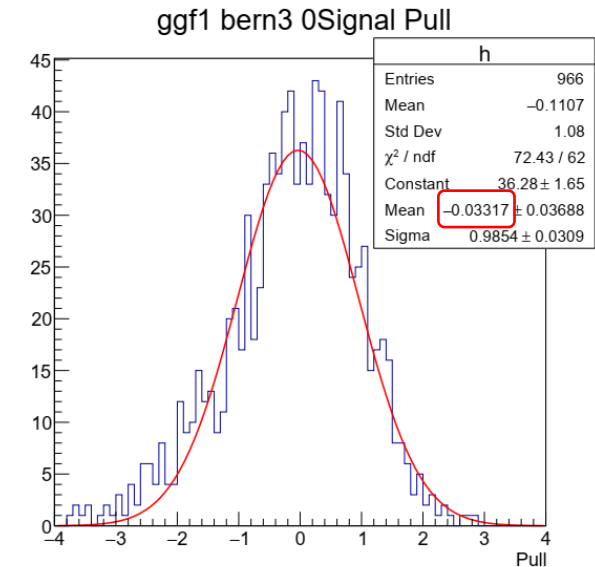


Untagged

([HIG-25-010](#))

Profile Bias and Signal Injection Test

- In the **profile bias test**, we generate 1000 background-only toys for each model in the envelope and estimate the envelope bias by performing a S+B fits on the toys
 - Toys fit with **the envelope**
 - The pull = $(N_{\text{sig fit}} - N_{\text{sig exp}}) / \sigma_{\text{sig fit}}$ should form a Gaussian whose mean is an estimate of the bias for the envelope
- To pass the test, all the members of the envelope should have bias smaller than 0.2
 - In cases with high bias, a heat map is used to determine the functions responsible for the biased fits
- **Signal injection test**, in principle, is the same test as the profile bias test, but where the toys are generating assuming $1\times$ or $5\times$ the nominal signal



Analysis Results Per Category

